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Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I ² C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	20
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 12x14b; D/A 4x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	24-VFQFN Exposed Pad
Supplier Device Package	24-QFN (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8lb12f64e-b-qfn24r

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Voltage DACs	Comparator 0 Inputs	Comparator 1 Inputs	Bootloader Type	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8LB12F64E-B-QSOP24	64	4352	21	13	4	6	7	UART	Yes	-40 to +105 °C	QSOP24
EFM8LB12F64ES0-B-QFN32	64	4352	29	20	4	10	9	SMBus	Yes	-40 to +105 °C	QFN32
EFM8LB12F64ES0-B-QFN24	64	4352	20	12	4	6	6	SMBus	Yes	-40 to +105 °C	QFN24
EFM8LB12F32E-B-QFN32	32	2304	29	20	4	10	9	UART	Yes	-40 to +105 °C	QFN32
EFM8LB12F32E-B-QFP32	32	2304	28	20	4	10	9	UART	Yes	-40 to +105 °C	QFP32
EFM8LB12F32E-B-QFN24	32	2304	20	12	4	6	6	UART	Yes	-40 to +105 °C	QFN24
EFM8LB12F32E-B-QSOP24	32	2304	21	13	4	6	7	UART	Yes	-40 to +105 °C	QSOP24
EFM8LB12F32ES0-B-QFN32	32	2304	29	20	4	10	9	SMBus	Yes	-40 to +105 °C	QFN32
EFM8LB12F32ES0-B-QFN24	32	2304	20	12	4	6	6	SMBus	Yes	-40 to +105 °C	QFN24
EFM8LB11F32E-B-QFN32	32	2304	29	20	2 ¹	10	9	UART	Yes	-40 to +105 °C	QFN32
EFM8LB11F32E-B-QFP32	32	2304	28	20	2 ¹	10	9	UART	Yes	-40 to +105 °C	QFP32
EFM8LB11F32E-B-QFN24	32	2304	20	12	2 ¹	6	6	UART	Yes	-40 to +105 °C	QFN24
EFM8LB11F32E-B-QSOP24	32	2304	21	13	2 ¹	6	7	UART	Yes	-40 to +105 °C	QSOP24
EFM8LB11F32ES0-B-QFN32	32	2304	29	20	2 ¹	10	9	SMBus	Yes	-40 to +105 °C	QFN32
EFM8LB11F32ES0-B-QFN24	32	2304	20	12	2 ¹	6	6	SMBus	Yes	-40 to +105 °C	QFN24
EFM8LB11F16E-B-QFN32	16	1280	29	20	2 ¹	10	9	UART	Yes	-40 to +105 °C	QFN32
EFM8LB11F16E-B-QFP32	16	1280	28	20	2 ¹	10	9	UART	Yes	-40 to +105 °C	QFP32
EFM8LB11F16E-B-QFN24	16	1280	20	12	2 ¹	6	6	UART	Yes	-40 to +105 °C	QFN24
EFM8LB11F16E-B-QSOP24	16	1280	21	13	2 ¹	6	7	UART	Yes	-40 to +105 °C	QSOP24
EFM8LB11F16ES0-B-QFN32	16	1280	29	20	2 ¹	10	9	SMBus	Yes	-40 to +105 °C	QFN32
EFM8LB11F16ES0-B-QFN24	16	1280	20	12	2 ¹	6	6	SMBus	Yes	-40 to +105 °C	QFN24
EFM8LB10F16E-B-QFN32	16	1280	29	20	0	10	9	UART	Yes	-40 to +105 °C	QFN32
EFM8LB10F16E-B-QFP32	16	1280	28	20	0	10	9	UART	Yes	-40 to +105 °C	QFP32
EFM8LB10F16E-B-QFN24	16	1280	20	12	0	6	6	UART	Yes	-40 to +105 °C	QFN24
EFM8LB10F16E-B-QSOP24	16	1280	21	13	0	6	7	UART	Yes	-40 to +105 °C	QSOP24
EFM8LB10F16ES0-B-QFN32	16	1280	29	20	0	10	9	SMBus	Yes	-40 to +105 °C	QFN32
EFM8LB10F16ES0-B-QFN24	16	1280	20	12	0	6	6	SMBus	Yes	-40 to +105 °C	QFN24

Note:

1. DAC0 and DAC1 are enabled on devices with 2 DACs available.

3. System Overview

3.1 Introduction

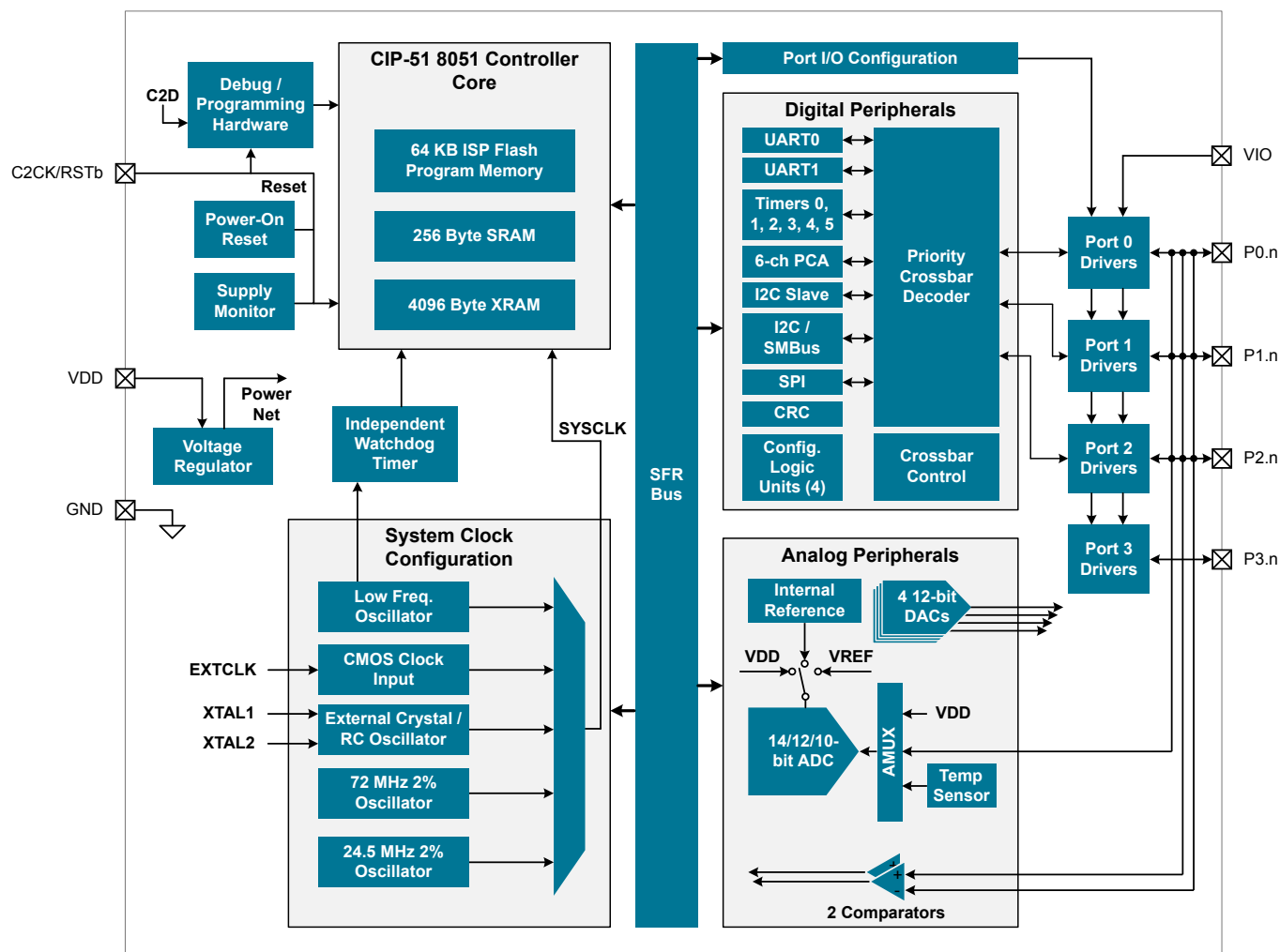


Figure 3.1. Detailed EFM8LB1 Block Diagram

Timers (Timer 0, Timer 1, Timer 2, Timer 3, Timer 4, and Timer 5)

Several counter/timers are included in the device: two are 16-bit counter/timers compatible with those found in the standard 8051, and the rest are 16-bit auto-reload timers for timing peripherals or for general purpose use. These timers can be used to measure time intervals, count external events and generate periodic interrupt requests. Timer 0 and Timer 1 are nearly identical and have four primary modes of operation. The other timers offer both 16-bit and split 8-bit timer functionality with auto-reload and capture capabilities.

Timer 0 and Timer 1 include the following features:

- Standard 8051 timers, supporting backwards-compatibility with firmware and hardware.
- Clock sources include SYSCLK, SYSCLK divided by 12, 4, or 48, the External Clock divided by 8, or an external pin.
- 8-bit auto-reload counter/timer mode
- 13-bit counter/timer mode
- 16-bit counter/timer mode
- Dual 8-bit counter/timer mode (Timer 0)

Timer 2, Timer 3, Timer 4, and Timer 5 are 16-bit timers including the following features:

- Clock sources for all timers include SYSCLK, SYSCLK divided by 12, or the External Clock divided by 8
- LFOSC0 divided by 8 may be used to clock Timer 3 and Timer 4 in active or suspend/snooze power modes
- Timer 4 is a low-power wake source, and can be chained together with Timer 3
- 16-bit auto-reload timer mode
- Dual 8-bit auto-reload timer mode
- External pin capture
- LFOSC0 capture
- Comparator 0 capture
- Configurable Logic output capture

Watchdog Timer (WDT0)

The device includes a programmable watchdog timer (WDT) running off the low-frequency oscillator. A WDT overflow forces the MCU into the reset state. To prevent the reset, the WDT must be restarted by application software before overflow. If the system experiences a software or hardware malfunction preventing the software from restarting the WDT, the WDT overflows and causes a reset. Following a reset, the WDT is automatically enabled and running with the default maximum time interval. If needed, the WDT can be disabled by system software or locked on to prevent accidental disabling. Once locked, the WDT cannot be disabled until the next system reset. The state of the RST pin is unaffected by this reset.

The Watchdog Timer has the following features:

- Programmable timeout interval
- Runs from the low-frequency oscillator
- Lock-out feature to prevent any modification until a system reset

3.6 Communications and Other Digital Peripherals

Universal Asynchronous Receiver/Transmitter (UART0)

UART0 is an asynchronous, full duplex serial port offering modes 1 and 3 of the standard 8051 UART. Enhanced baud rate support allows a wide range of clock sources to generate standard baud rates. Received data buffering allows UART0 to start reception of a second incoming data byte before software has finished reading the previous data byte.

The UART module provides the following features:

- Asynchronous transmissions and receptions.
- Baud rates up to $\text{SYSCLK}/2$ (transmit) or $\text{SYSCLK}/8$ (receive).
- 8- or 9-bit data.
- Automatic start and stop generation.
- Single-byte FIFO on transmit and receive.

3.7 Analog

14/12/10-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 14-, 12-, and 10-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 20 external inputs
- Single-ended 14-bit, 12-bit and 10-bit modes
- Supports an output update rate of up to 1 Msps in 12-bit mode
- Channel sequencer logic with direct-to-XDATA output transfers
- Operation in a low power mode at lower conversion speeds
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Output data window comparator allows automatic range checking
- Support for output data accumulation
- Conversion complete and window compare interrupts supported
- Flexible output data formatting
- Includes a fully-internal fast-settling 1.65 V reference and an on-chip precision 2.4 / 1.2 V reference, with support for using the supply as the reference, an external reference and signal ground
- Integrated factory-calibrated temperature sensor

12-Bit Digital-to-Analog Converters (DAC0, DAC1, DAC2, DAC3)

The DAC modules are 12-bit Digital-to-Analog Converters with the capability to synchronize multiple outputs together. The DACs are fully configurable under software control. The voltage reference for the DACs is selectable between internal and external reference sources.

- Voltage output with 12-bit performance
- Hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Outputs may be configured to persist through reset and maintain output state to avoid system disruption
- Multiple DAC outputs can be synchronized together
- DAC pairs (DAC0 and 1 or DAC2 and 3) support complementary output waveform generation
- Outputs may be switched between two levels according to state of configurable logic / PWM input trigger
- Flexible input data formatting
- Supports references from internal supply, on-chip precision reference, or external VREF pin

Low Current Comparators (CMP0, CMP1)

An analog comparator is used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator includes the following features:

- Up to 10 (CMP0) or 9 (CMP1) external positive inputs
- Up to 10 (CMP0) or 9 (CMP1) external negative inputs
- Additional input options:
 - Internal connection to LDO output
 - Direct connection to GND
 - Direct connection to VDD
 - Dedicated 6-bit reference DAC
- Synchronous and asynchronous outputs can be routed to pins via crossbar
- Programmable hysteresis between 0 and ± 20 mV
- Programmable response time
- Interrupts generated on rising, falling, or both edges
- PWM output kill feature

3.10 Bootloader

All devices come pre-programmed with a UART0 bootloader or an SMBus bootloader. These bootloaders reside in the code security page, which is the last page of code flash; they can be erased if they are not needed.

The byte before the Lock Byte is the Bootloader Signature Byte. Setting this byte to a value of 0xA5 indicates the presence of the bootloader in the system. Any other value in this location indicates that the bootloader is not present in flash.

When a bootloader is present, the device will jump to the bootloader vector after any reset, allowing the bootloader to run. The bootloader then determines if the device should stay in bootload mode or jump to the reset vector located at 0x0000. When the bootloader is not present, the device will jump to the reset vector of 0x0000 after any reset.

More information about the bootloader protocol and usage can be found in *AN945: EFM8 Factory Bootloader User Guide*. Application notes can be found on the Silicon Labs website (www.silabs.com/8bit-appnotes) or within Simplicity Studio by using the [Application Notes] tile.

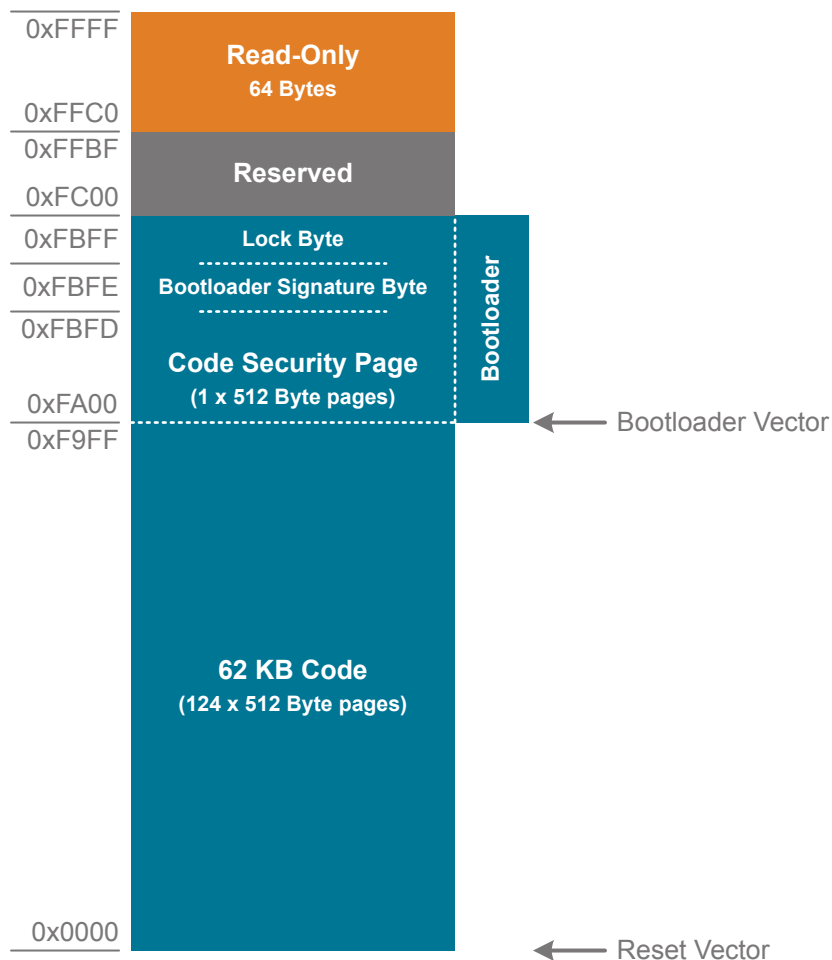


Figure 3.2. Flash Memory Map with Bootloader — 62.5 KB Devices

Table 3.2. Summary of Pins for Bootloader Communication

Bootloader	Pins for Bootload Communication
UART	TX – P0.4
	RX – P0.5
SMBus	P0.2 – SDA ¹
	P0.3 – SCL ¹

4.1.2 Power Consumption

Table 4.2. Power Consumption

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Digital Core Supply Current						
Normal Mode-Full speed with code executing from flash	I_{DD}	$F_{SYSCLK} = 72 \text{ MHz (HFOSC1)}^2$	—	12.9	15	mA
		$F_{SYSCLK} = 24.5 \text{ MHz (HFOSC0)}^2$	—	4.2	5	mA
		$F_{SYSCLK} = 1.53 \text{ MHz (HFOSC0)}^2$	—	625	1050	μA
		$F_{SYSCLK} = 80 \text{ kHz}^3$	—	155	575	μA
Idle Mode-Core halted with peripherals running	I_{DD}	$F_{SYSCLK} = 72 \text{ MHz (HFOSC1)}^2$	—	9.6	11.1	mA
		$F_{SYSCLK} = 24.5 \text{ MHz (HFOSC0)}^2$	—	3.14	3.8	mA
		$F_{SYSCLK} = 1.53 \text{ MHz (HFOSC0)}^2$	—	520	950	μA
		$F_{SYSCLK} = 80 \text{ kHz}^3$	—	135	550	μA
Suspend Mode-Core halted and high frequency clocks stopped, Supply monitor off.	I_{DD}	LFO Running	—	125	545	μA
		LFO Stopped	—	120	535	μA
Snooze Mode-Core halted and high frequency clocks stopped. Regulator in low-power state, Supply monitor off.	I_{DD}	LFO Running	—	23	430	μA
		LFO Stopped	—	19	425	μA
Stop Mode—Core halted and all clocks stopped, Internal LDO On, Supply monitor off.	I_{DD}		—	120	535	μA
Shutdown Mode—Core halted and all clocks stopped, Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	2.1	μA
Analog Peripheral Supply Currents						
High-Frequency Oscillator 0	I_{HFOSC0}	Operating at 24.5 MHz, $T_A = 25^\circ\text{C}$	—	120	135	μA
High-Frequency Oscillator 1	I_{HFOSC1}	Operating at 72 MHz, $T_A = 25^\circ\text{C}$	—	1285	1340	μA
Low-Frequency Oscillator	I_{LFOSC}	Operating at 80 kHz, $T_A = 25^\circ\text{C}$	—	3.7	6	μA

4.1.5 Power Management Timing

Table 4.5. Power Management Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Idle Mode Wake-up Time	t_{IDLEWK}		2	—	3	SYSCCLKs
Suspend Mode Wake-up Time	$t_{SUS-PENDWK}$	SYSCCLK = HFOSC0 CLKDIV = 0x00	—	170	—	ns
Snooze Mode Wake-up Time	$t_{SLEEPWK}$	SYSCCLK = HFOSC0 CLKDIV = 0x00	—	12	—	μ s

4.1.6 Internal Oscillators

Table 4.6. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
High Frequency Oscillator 0 (24.5 MHz)						
Oscillator Frequency	f_{HFOSC0}	Full Temperature and Supply Range	24	24.5	25	MHz
Power Supply Sensitivity	PSS_{HFOSC0}	$T_A = 25\text{ }^{\circ}\text{C}$	—	0.5	—	%/V
Temperature Sensitivity	TS_{HFOSC0}	$V_{DD} = 3.0\text{ V}$	—	40	—	ppm/ $^{\circ}\text{C}$
High Frequency Oscillator 1 (72 MHz)						
Oscillator Frequency	f_{HFOSC1}	Full Temperature and Supply Range	70.5	72	73.5	MHz
Power Supply Sensitivity	PSS_{HFOSC1}	$T_A = 25\text{ }^{\circ}\text{C}$	—	300	—	ppm/V
Temperature Sensitivity	TS_{HFOSC1}	$V_{DD} = 3.0\text{ V}$	—	103	—	ppm/ $^{\circ}\text{C}$
Low Frequency Oscillator (80 kHz)						
Oscillator Frequency	f_{LFOSC}	Full Temperature and Supply Range	75	80	85	kHz
Power Supply Sensitivity	PSS_{LFOSC}	$T_A = 25\text{ }^{\circ}\text{C}$	—	0.05	—	%/V
Temperature Sensitivity	TS_{LFOSC}	$V_{DD} = 3.0\text{ V}$	—	65	—	ppm/ $^{\circ}\text{C}$

4.1.9 ADC

Table 4.9. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N _{bits}	14 Bit Mode	14			Bits
		12 Bit Mode	12			Bits
		10 Bit Mode	10			Bits
Throughput Rate (High Speed Mode)	f _S	14 Bit Mode	—	—	900	ksps
		12 Bit Mode	—	—	1	Msps
		10 Bit Mode	—	—	1.125	Msps
Throughput Rate (Low Power Mode)	f _S	14 Bit Mode	—	—	320	ksps
		12 Bit Mode	—	—	340	ksps
		10 Bit Mode	—	—	360	ksps
Tracking Time	t _{TRK}	High Speed Mode	217.8 ¹	—	—	ns
		Low Power Mode	450	—	—	ns
Power-On Time	t _{PWR}		1.2	—	—	μs
SAR Clock Frequency	f _{SAR}	High Speed Mode	—	—	18.36	MHz
		Low Power Mode	—	—	12.25	MHz
Conversion Time ²	t _{CNV}	14-Bit Conversion, SAR Clock = 18 MHz, System Clock = 72 MHz.	0.81			μs
		12-Bit Conversion, SAR Clock = 18 MHz, System Clock = 72 MHz.	0.7			μs
		10-Bit Conversion, SAR Clock = 18 MHz, System Clock = 72 MHz.	0.59			μs
Sample/Hold Capacitor	C _{SAR}	Gain = 1	—	5.2	—	pF
		Gain = 0.75	—	3.9	—	pF
		Gain = 0.5	—	2.6	—	pF
		Gain = 0.25	—	1.3	—	pF
Input Pin Capacitance	C _{IN}	High Quality Input	—	20	—	pF
		Normal Input	—	20	—	pF
Input Mux Impedance	R _{MUX}	High Quality Input	—	330	—	Ω
		Normal Input	—	550	—	Ω
Voltage Reference Range	V _{REF}		1	—	V _{IO}	V
Input Voltage Range ³	V _{IN}		0	—	V _{REF} / Gain	V

4.1.11 Temperature Sensor

Table 4.11. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Uncalibrated Offset	V_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	751	—	mV
Uncalibrated Offset Error ¹	E_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	19	—	mV
Slope	M		—	2.82	—	mV/ $^{\circ}\text{C}$
Slope Error ¹	E_M		—	29	—	$\mu\text{V}/^{\circ}\text{C}$
Linearity	LIN	$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	—	-0.1 to 0.15	—	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	—	-0.2 to 0.35	—	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	—	-0.4 to 0.8	—	$^{\circ}\text{C}$
Turn-on Time	t_{ON}		—	3.5	—	μs
Temp Sensor Error Using Typical Slope and Factory-Calibrated Offset ^{2, 3}	E_{TOT}	$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	-2.6	—	1.8	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	-2.9	—	2.7	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	-3.2	—	4.2	$^{\circ}\text{C}$

Note:

1. Represents one standard deviation from the mean.
2. The factory-calibrated offset value is stored in the read-only area of flash in locations 0xFFD4 (low byte) and 0xFFD5 (high byte). The 14-bit result represents the output of the ADC when sampling the temp sensor using the 1.65 V internal voltage reference.
3. The temp sensor error includes the offset calibration error, slope error, and linearity error. The values are based upon characterization and are not tested across temperature in production. The values represent three standard deviations above and below the mean. Additional information on achieving high measurement accuracy is available in AN929: Accurate Temperature Sensing with the EFM8 Laser Bee MCU Family.

4.1.16 SMBus

Table 4.16. SMBus Peripheral Timing Performance (Master Mode)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Standard Mode (100 kHz Class)						
I2C Operating Frequency	f_{I2C}		0	—	70^2	kHz
SMBus Operating Frequency	f_{SMB}		40^1	—	70^2	kHz
Bus Free Time Between STOP and START Conditions	t_{BUF}		9.4	—	—	μs
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		4.7	—	—	μs
Repeated START Condition Setup Time	$t_{SU:STA}$		9.4	—	—	μs
STOP Condition Setup Time	$t_{SU:STO}$		9.4	—	—	μs
Data Hold Time	$t_{HD:DAT}$		0	—	—	μs
Data Setup Time	$t_{SU:DAT}$		4.7	—	—	μs
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	t_{LOW}		4.7	—	—	μs
Clock High Period	t_{HIGH}		9.4	—	50^3	μs
Fast Mode (400 kHz Class)						
I2C Operating Frequency	f_{I2C}		0	—	256^2	kHz
SMBus Operating Frequency	f_{SMB}		40^1	—	256^2	kHz
Bus Free Time Between STOP and START Conditions	t_{BUF}		2.6	—	—	μs
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		1.3	—	—	μs
Repeated START Condition Setup Time	$t_{SU:STA}$		2.6	—	—	μs
STOP Condition Setup Time	$t_{SU:STO}$		2.6	—	—	μs
Data Hold Time	$t_{HD:DAT}$		0	—	—	μs
Data Setup Time	$t_{SU:DAT}$		1.3	—	—	μs
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	t_{LOW}		1.3	—	—	μs
Clock High Period	t_{HIGH}		2.6	—	50^3	μs

Note:

1. The minimum SMBus frequency is limited by the maximum Clock High Period requirement of the SMBus specification.
2. The maximum I2C and SMBus frequencies are limited by the minimum Clock Low Period requirements of their respective specifications.
3. SMBus has a maximum requirement of 50 μs for Clock High Period. Operating frequencies lower than 40 kHz will be longer than 50 μs . I2C can support periods longer than 50 μs .

4.3 Absolute Maximum Ratings

Stresses above those listed in [Table 4.19 Absolute Maximum Ratings on page 30](#) may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at <http://www.silabs.com/support/quality/pages/default.aspx>.

Table 4.19. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		-55	125	°C
Storage Temperature	T_{STG}		-65	150	°C
Voltage on VDD	V_{DD}		GND-0.3	4.2	V
Voltage on VIO ²	V_{IO}		GND-0.3	$V_{DD}+0.3$	V
Voltage on I/O pins or RSTb, excluding P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}	$V_{IO} > 3.3\text{ V}$	GND-0.3	5.8	V
		$V_{IO} < 3.3\text{ V}$	GND-0.3	$V_{IO}+2.5$	V
Voltage on P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}		GND-0.3	$V_{DD}+0.3$	V
Total Current Sunk into Supply Pin	I_{VDD}		—	400	mA
Total Current Sourced out of Ground Pin	I_{GND}		400	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	I_{IO}		-100	100	mA
Operating Junction Temperature	T_J	$T_A = -40\text{ °C to }105\text{ °C}$	-40	130	°C

Note:

1. Exposure to maximum rating conditions for extended periods may affect device reliability.
2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.

Table 6.1. Pin Definitions for EFM8LB1x-QFN32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
2	VIO	I/O Supply Power Input			
3	VDD	Supply Power Input			
4	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
5	P3.7 / C2D	Multifunction I/O / C2 Debug Data			
6	P3.4	Multifunction I/O			
7	P3.3	Multifunction I/O			DAC3
8	P3.2	Multifunction I/O			DAC2
9	P3.1	Multifunction I/O			DAC1
10	P3.0	Multifunction I/O			DAC0
11	P2.6	Multifunction I/O			ADC0.19 CMP1P.8 CMP1N.8
12	P2.5	Multifunction I/O		CLU3OUT	ADC0.18 CMP1P.7 CMP1N.7
13	P2.4	Multifunction I/O			ADC0.17 CMP1P.6 CMP1N.6
14	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	ADC0.16 CMP1P.5 CMP1N.5

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
23	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12	ADC0.8 CMP0P.8 CMP0N.8
24	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.13	ADC0.7 CMP0P.7 CMP0N.7
25	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU1OUT CLU0A.12 CLU1A.10 CLU2A.10 CLU3B.12	ADC0.6 CMP0P.6 CMP0N.6 CMP1P.1 CMP1N.1
26	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.0 CMP1N.0
27	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4
28	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9 CLU3B.11	ADC0.3 CMP0P.3 CMP0N.3

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
29	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8 CLU3B.10	ADC0.2 CMP0P.2 CMP0N.2
30	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.9 CLU3A.9	XTAL2
31	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2 CLU0OUT CLU0A.9 CLU2B.8 CLU3A.8	XTAL1 ADC0.1 CMP0P.1 CMP0N.1
32	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND
Center	GND	Ground			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
18	P1.7	Multifunction I/O	Yes	P1MAT.7 CLU0B.15 CLU1B.13 CLU2A.13	ADC0.13 CMP0P.9 CMP0N.9
19	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU0A.15 CLU1B.12 CLU2A.12	ADC0.12
20	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU0B.14 CLU1A.13 CLU2B.13	ADC0.11
21	P1.4	Multifunction I/O	Yes	P1MAT.4 CLU0A.14 CLU1A.12 CLU2B.12	ADC0.10
22	P1.3	Multifunction I/O	Yes	P1MAT.3 CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	ADC0.9
23	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12	ADC0.8 CMP0P.8 CMP0N.8
24	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.13	ADC0.7 CMP0P.7 CMP0N.7

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
30	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.9 CLU3A.9	XTAL2
31	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2 CLU0OUT CLU0A.9 CLU2B.8 CLU3A.8	XTAL1 ADC0.1 CMP0P.1 CMP0N.1
32	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
24	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8 CLU3B.10	ADC0.2 CMP0P.2 CMP0N.2

8. QFP32 Package Specifications

8.1 QFP32 Package Dimensions

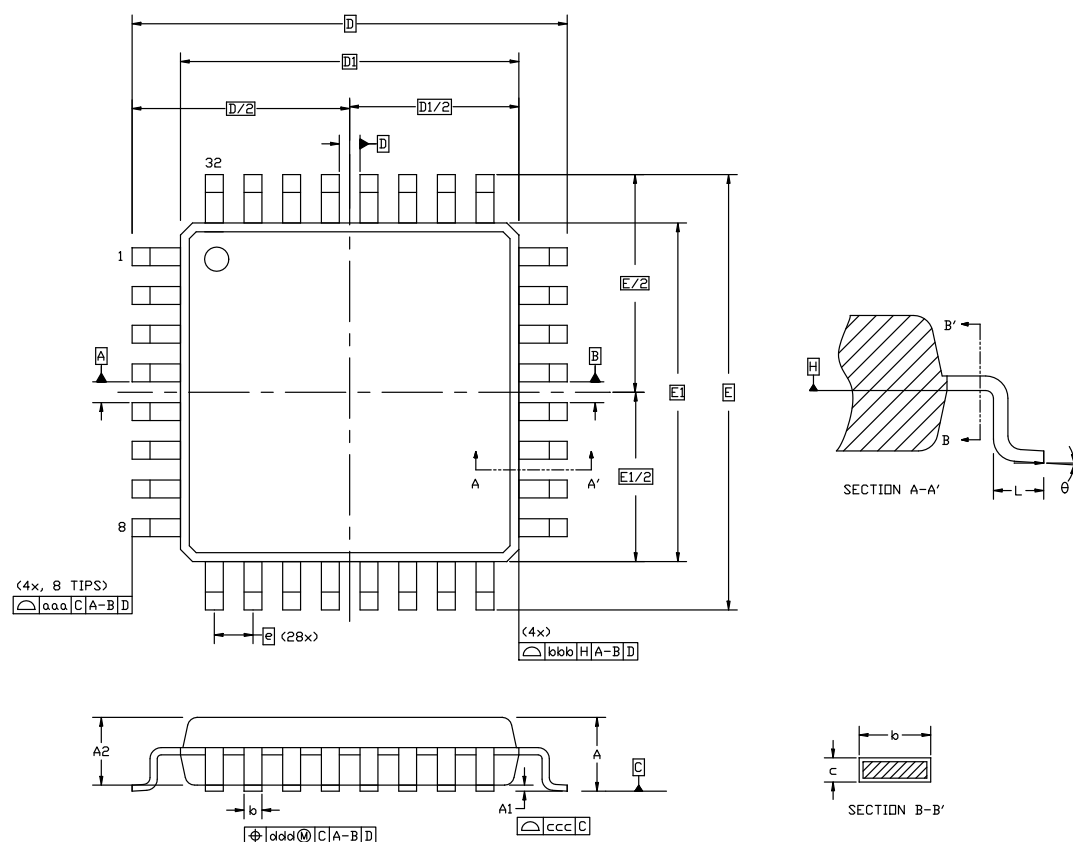


Figure 8.1. QFP32 Package Drawing

Table 8.1. QFP32 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.20
A1	0.05	—	0.15
A2	0.95	1.00	1.05
b	0.30	0.37	0.45
c	0.09	—	0.20
D	9.00 BSC		
D1	7.00 BSC		
e	0.80 BSC		
E	9.00 BSC		
E1	7.00 BSC		
L	0.50	0.60	0.70

10.2 QSOP24 PCB Land Pattern

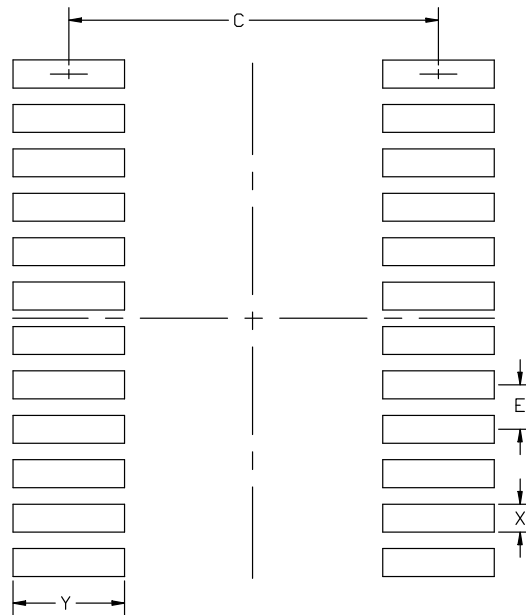


Figure 10.2. QSOP24 PCB Land Pattern Drawing

Table 10.2. QSOP24 PCB Land Pattern Dimensions

Dimension	Min	Max
C	5.20	5.30
E	0.635 BSC	
X	0.30	0.40
Y	1.50	1.60

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This land pattern design is based on the IPC-7351 guidelines.
3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μ m minimum, all the way around the pad.
4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
5. The stencil thickness should be 0.125 mm (5 mils).
6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
7. A No-Clean, Type-3 solder paste is recommended.
8. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

11. Revision History

11.1 Revision 1.01

October 21st, 2016

Updated QFN24 center pad stencil description.

11.2 Revision 1.0

September 6th, 2016

Updated part numbers to revision B.

Updated many specifications with full characterization data.

Added a note regarding which DACs are available to [Table 2.1 Product Selection Guide on page 2](#).

Added specifications for [4.1.16 SMBus](#).

Added bootloader pinout information to [3.10 Bootloader](#).

Added CRC Calculation Time to [4.1.4 Flash Memory](#).

11.3 Revision 0.5

February 10th, 2016

Updated [Figure 5.2 Debug Connection Diagram on page 32](#) to move the pull-up resistor on C2D / RSTb to after the series resistor instead of before.

Added S0 devices and information about the SMBus bootloader in [3.10 Bootloader](#).

Added a reference to *AN945: EFM8 Factory Bootloader User Guide* in [3.10 Bootloader](#).

Added mention of the pre-programmed bootloaders in [1. Feature List](#).

Updated all part numbers to revision B.

Added the C oscillator, which is now available on revision B.

Adjusted C1, C2, X2, Y2, and Y1 maximums for [7.2 QFN32 PCB Land Pattern](#).

Adjusted package markings for QFN32 and QSOP24 packages.

Filled in TBD minimum and maximum values for DAC Differential Nonlinearity in [Table 4.12 DACs on page 24](#).

11.4 Revision 0.4

Updated specification tables based on current device characterization status and production test limits.

Added bootloader section.

Added typical connection diagrams.

Corrected CLU connections in pin function tables.

11.5 Revision 0.3

Added information on the bootloader to [3.10 Bootloader](#).

Updated some characterization TBD values.

11.6 Revision 0.1

Initial release.